

<b>Search Notes</b> 	<b>Application/Control No.</b>	<b>Applicant(s)/Patent under Reexamination</b>
	10/642,343	GIESSLER ET AL.
	<b>Examiner</b> Sara Addisu	<b>Art Unit</b> 3722

**SEARCHED**

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Dan Howell	6/7/2005	SA
Inventor name search	11/16/2005	SA
Consulted Hwei Su Payer about restricting claims 11-14 in class 76/108.6. Agreed	6/7/2005	SA
Consulted H. Payer about traverse to restricting claims 11-14. FIB (focused Ion Beam) is known as an alternative to grinding	11/17/2005	SA

<b>INTERFERENCE SEARCHED</b>			
<b>Class</b>	<b>Subclass</b>	<b>Date</b>	<b>Examiner</b>